

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277
: :
Masahiro NAKAYAMA, et al. : Confirmation Number:
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Serial No.: : Group Art Unit:
: :
Filed: September 10, 2003 : Examiner: Unknown
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For: OBVERSE/REVERSE DISCRIMINATIVE RECTANGULAR NITRIDE
SEMICONDUCTOR WAFER

INFORMATION DISCLOSURE STATEMENT

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Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

The relevance of the listed documents on attached Form 1449 are discussed in the present specification.

Serial No.:

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Respectfully submitted,

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)			ATTY. DOCKET NO. 52775-023	SERIAL NO.		
			APPLICANT Masahiro NAKAYAMA, et al.			
			FILING DATE September 10, 2003	GROUP		
U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ₂ (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
	US					
	US					
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FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number &-Kind Codes (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation
						Yes
		JP 2-144908	06/04/1990	HITACHI LTD		(Japan w/English Abstract)
		JP 60-167426	08/30/1985	NEC CORP		(Japan w/English Abstract)
		JP P2000-331898A	11/30/2000	HITACHI CABLE LTD		(Japan w/English Abstract)
		JP 58-71616	04/28/1983	NEC HOME ELECTRONICS LTD		(Japan w/English Abstract)
		JP 8-316112	11/29/1996	KOMATSU ELECTRON METALS CO LTD		(Japan w/English Abstract)
		JP P2002-356398A	12/13/2002	SUMITOMO ELECTRIC IND LTD		(Japan w/English Abstract)
		JP P2002-222746A	08/09/2002	MATSUSHITA ELECTRIC IND CO LTD		(Japan w/English Abstract)
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)						
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				
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Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.